National Semiconductor

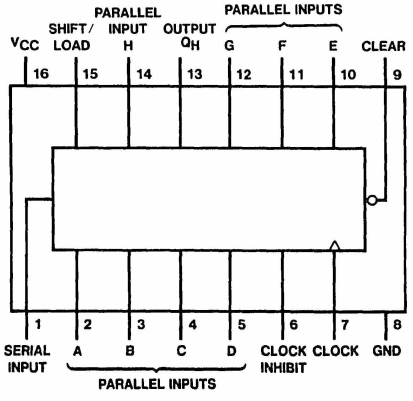
DM54166
8-Bit Parallel In/Serial Out Shift Registers

General Description

These parallel-in or serial-in, serial-out shift registers feature gated clock inputs and an overriding clear input. All inputs are buffered to lower the drive requirements to one normalized load, and input clamping diodes minimize switching transients to simplify system design. The load mode is established by the shift/load input. When high, this input enables the serial data input and couples the eight flip-flops for serial shifting with each clock pulse. When low, the parallel (broadside) data inputs are enabled and synchronous loading occurs on the next clock pulse. During parallel loading, serial data flow is inhibited. Clocking is accomplished on the low-to-high-level edge of the clock pulse through a two-input NOR gate, permitting one input to be used as a clock-enable or clock-inhibit function. Holding either of the clock inputs high inhibits clocking; holding either low enables the other clock input. This allows the system clock to be free-running, and the register can be stopped on command with the other clock input. The clock-inhibit input should be changed to the high level only while the clock input is high. A buffered, direct clear input overrides all other inputs, including the clock, and sets all flip-flops to zero.

Connection Diagram

Dual-In-Line Package



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Order Number DM54166J
See NS Package Number J16A

Function Table

Inputs						Internal Outputs		Output
Clear	Shift/ Load	Clock Inhibit	Clock	Serial	Parallel A...H	Q_A	Q_B	Q_H
L	X	X	X	X	X	L	L	L
H	X	L	L	X	X	Q_{A0}	Q_{B0}	Q_{H0}
H	L	L	↑	X	a...h	a	b	h
H	H	L	↑	H	X	H	Q_{An}	Q_{Gn}
H	H	L	↑	L	X	L	Q_{An}	Q_{Gn}
H	X	H	↑	X	X	Q_{A0}	Q_{B0}	Q_{H0}

H = High Level (steady state), L = Low Level (steady state)

X = Don't Care (any input, including transitions)

↑ = Transition from Low to High Level

a . . . h = The level of stead-state input at inputs A through H, respectively

Q_{A0}, Q_{B0}, Q_{H0} = The level of Q_A, Q_B, Q_H, respectively, before the indicated steady-state input conditions were established

Q_{An}, Q_{Gn} = The level of Q_A, Q_G, respectively, before the most recent ↑ transition of the clock

Absolute Maximum Ratings (Note)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage	7V
Input Voltage	5.5V
Operating Free Air Temperature Range	
DM54	−55°C to +125°C
Storage Temperature Range	−65°C to +150°C

Note: *The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the "Electrical Characteristics" table are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.*

Recommended Operating Conditions

Symbol	Parameter		DM54166			Units
			Min	Nom	Max	
V_{CC}	Supply Voltage		4.5	5	5.5	V
V_{IH}	High Level Input Voltage		2			V
V_{IL}	Low Level Input Voltage				0.8	V
I_{OH}	High Level Output Current				−0.8	mA
I_{OL}	Low Level Output Current				16	mA
f_{CLK}	Clock Frequency (Note 4)		0		25	MHz
t_W	Pulse Width (Note 4)	Clock	24			ns
		Clear	20			
t_{SU}	Setup Time (Note 4)	Mode	30			ns
		Data	20			
t_H	Data Hold Time (Note 4)		0			ns
T_A	Free Air Operating Temperature		−55		125	°C

Electrical Characteristics over recommended operating free air temperature range (unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ (Note 1)	Max	Units
V_I	Input Clamp Voltage	V_{CC} = Min, I_I = −12 mA			−1.5	V
V_{OH}	High Level Output Voltage	V_{CC} = Min, I_{OH} = Max V_{IL} = Max, V_{IH} = Min	2.4			V
V_{OL}	Low Level Output Voltage	V_{CC} = Min, I_{OL} = Max V_{IH} = Min, V_{IL} = Max			0.4	V
I_I	Input Current @ Max Input Voltage	V_{CC} = Max, V_I = 5.5V			1	mA
I_{IH}	High Level Input Current	V_{CC} = Max, V_I = 2.4V			40	μA
I_{IL}	Low Level Input Current	V_{CC} = Max, V_I = 0.4V			−1.6	mA
I_{OS}	Short Circuit Output Current	V_{CC} = Max (Note 2)	−20		−57	mA
I_{CC}	Supply Current	V_{CC} = Max (Note 3)		72	104	mA

Note 1: All typicals are at V_{CC} = 5V, T_A = 25°C.

Note 2: Not more than one output should be shorted at a time.

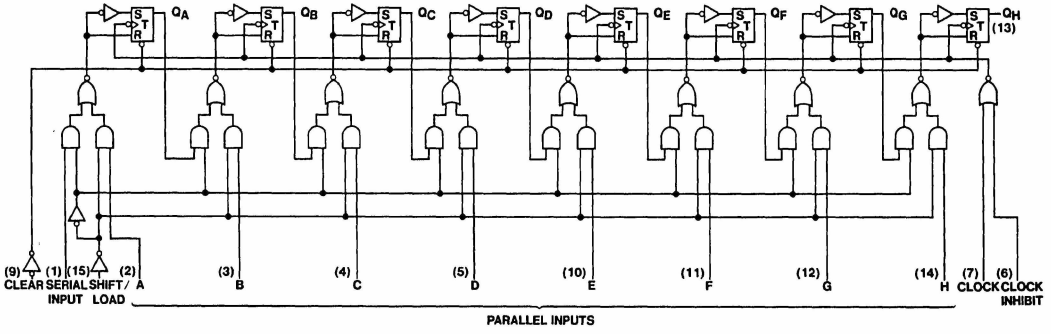
Note 3: With all outputs open, 4.5V applied to the SERIAL input, all other inputs except CLOCK grounded, I_{CC} is measured after a momentary ground, then 4.5V, is applied to the CLOCK.

Note 4: T_A = 25°C and V_{CC} = 5V.

Switching Characteristics at V_{CC} = 5V and T_A = 25°C (See Section 1 for Test Waveforms and Output Load)

Symbol	Parameter	From (Input) To (Output)	R_L = 400Ω, C_L = 15 pF		Units
			Min	Max	
f_{MAX}	Maximum Clock Frequency		25		MHz
t_{PLH}	Propagation Delay Time Low to High Level Output	Clock to Output	8	26	ns
t_{PHL}	Propagation Delay Time High to Low Level Output	Clock to Output	8	30	ns
t_{PHL}	Propagation Delay Time High to Low Level Output	Clear to Output		35	ns

Logic Diagram



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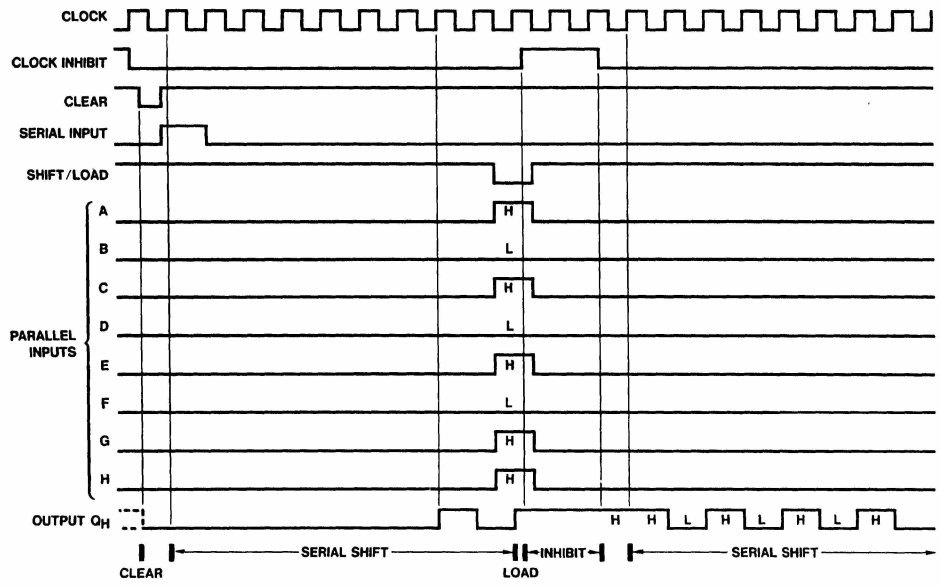
Timing Diagram

Typical Clear, Shift, Load, Inhibit, and Shift Sequences



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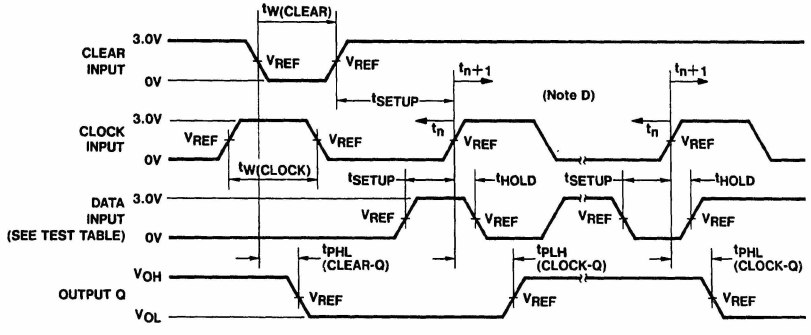
Parameter Measurement Information

Voltage Waveforms



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Test Table for Synchronous Inputs

Data Input For Test	Shift/Load	Output Tested (See Note C)
H	0V	Q_H at $T_N + 1$
Serial Input	4.5V	Q_H at $T_N + 8$

Note A: The clock pulse has the following characteristics:
$t_{W(clock)} \geq 20$ ns and PRR = 1 MHz.
The clear pulse has the following characteristics:
$t_{W(clear)} \geq 20$ ns and $t_{HOLD} = 0$ ns.
When testing f_{MAX}, vary the clock PRR.

Note B: A clear pulse is applied prior to each test.

Note C: Propagation delay times (t_{PLH} and t_{PHL}) are measured at t_{n+1}. Proper shifting of data is verified at t_{n+8} with a functional test.

Note D: t_n = bit time before clocking transition.
t_{n+1} = bit time after one clocking transition.
t_{n+8} = bit time after eight clocking transitions.

Note E: $V_{REF} = 1.5$V for 166.